

Press Release

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New Software from Polytec Enhances Surface Metrology Features of TopMap

Polytec announces the release of TMS 3.1, a comprehensive revision of its measurement and analysis software for the TopMap series of optical surface profilometers. In addition to being easy-to-use, the TMS software, developed under .NET, offers features that include extended analysis options, automation with c# scripting (add-ins), a multi-document interface and a particularly powerful and innovative 3D visualization module. This new software is available immediately for all TopMap interferometers .

Polytec's TopMap series of white light interferometers, available in several models, is designed to handle rapid production line throughput and high-resolution laboratory measurements. All TopMap models are equipped with Polytec's user-friendly TMS software.

- As a complete measurement station, the TMS-100 TopMap Metro.Lab is perfectly suited for large-area measurement of planarity and parallelism. The wide vertical dynamic range of 70 mm enables even relatively large workpieces with deep features to be measured accurately.
- The TMS-300 TopMap In.Line is optimized for precise measurement of surfaces in demanding production control environments.
- And the TMS-1200 TopMap μ .Lab, with its higher spatial resolution, is the ideal system for measuring the topography of microstructures and the fine structure of working surfaces.

No publication fee – file copy requested

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